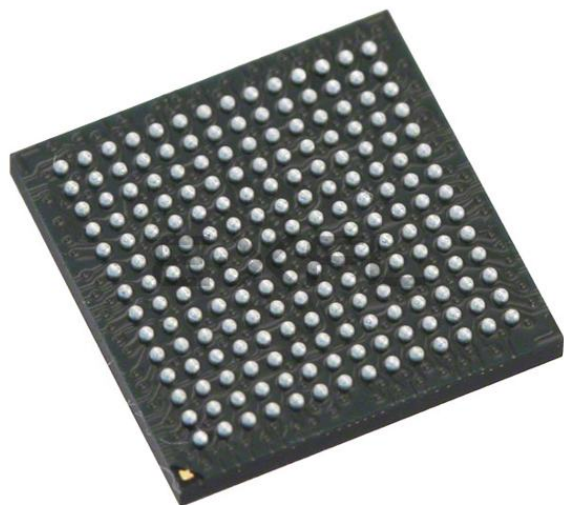




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	1139
Number of Logic Elements/Cells	14579
Total RAM Bits	589824
Number of I/O	106
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	196-TFBGA, CSBGA
Supplier Device Package	196-CSPBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx16-l1cpg196c

Table 2: Recommended Operating Conditions⁽¹⁾

Symbol	Description			Min	Typ	Max	Units
V _{CCINT}	Internal supply voltage relative to GND	-3, -3N, -2	Standard performance ⁽²⁾	1.14	1.2	1.26	V
		-3, -2	Extended performance ⁽²⁾	1.2	1.23	1.26	V
		-1L	Standard performance ⁽²⁾	0.95	1.0	1.05	V
V _{CCAUX} ⁽³⁾⁽⁴⁾	Auxiliary supply voltage relative to GND	V _{CCAUX} = 2.5V ⁽⁵⁾		2.375	2.5	2.625	V
		V _{CCAUX} = 3.3V		3.15	3.3	3.45	V
V _{CCO} ⁽⁶⁾⁽⁷⁾⁽⁸⁾	Output supply voltage relative to GND			1.1	–	3.45	V
V _{IN}	Input voltage relative to GND	All I/O standards (except PCI)	Commercial temperature (C)	–0.5	–	4.0	V
			Industrial temperature (I)	–0.5	–	3.95	V
			Expanded (Q) temperature	–0.5	–	3.95	V
		PCI I/O standard ⁽⁹⁾		–0.5	–	V _{CCO} + 0.5	V
I _{IN} ⁽¹⁰⁾	Maximum current through pin using PCI I/O standard when forward biasing the clamp diode. ⁽⁹⁾	Commercial (C) and Industrial temperature (I)		–	–	10	mA
		Expanded (Q) temperature		–	–	7	mA
V _{BATT} ⁽¹¹⁾	Battery voltage relative to GND, T _j = 0°C to +85°C (LX75, LX75T, LX100, LX100T, LX150, and LX150T only)			1.0	–	3.6	V
T _j	Junction temperature operating range	Commercial (C) range		0	–	85	°C
		Industrial temperature (I) range		–40	–	100	°C
		Expanded (Q) temperature range		–40	–	125	°C

Notes:

- All voltages are relative to ground.
- See *Interface Performances for Memory Interfaces* in Table 25. The extended performance range is specified for designs not using the standard V_{CCINT} voltage range. The standard V_{CCINT} voltage range is used for:
 - Designs that do not use an MCB
 - LX4 devices
 - Devices in the TQG144 or CPG196 packages
 - Devices with the -3N speed grade
- Recommended maximum voltage droop for V_{CCAUX} is 10 mV/ms.
- During configuration, if V_{CCO_2} is 1.8V, then V_{CCAUX} must be 2.5V.
- The -1L devices require $V_{CCAUX} = 2.5V$ when using the LVDS_25, LVDS_33, BLVDS_25, LVPECL_25, RSDS_25, RSDS_33, PPDS_25, and PPDS_33 I/O standards on inputs. LVPECL_33 is not supported in the -1L devices.
- Configuration data is retained even if V_{CCO} drops to 0V.
- Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
- For PCI systems, the transmitter and receiver should have common supplies for V_{CCO} .
- Devices with a -1L speed grade do not support Xilinx PCI IP.
- Do not exceed a total of 100 mA per bank.
- V_{BATT} is required to maintain the battery backed RAM (BBR) AES key when V_{CCAUX} is not applied. Once V_{CCAUX} is applied, V_{BATT} can be unconnected. When BBR is not used, Xilinx recommends connecting to V_{CCAUX} or GND. However, V_{BATT} can be unconnected.

Table 5: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	LX4	2.5	2.5	2.5	2.5	mA
		LX9	2.5	2.5	2.5	2.5	mA
		LX16	3.0	3.0	3.0	3.0	mA
		LX25	4.0	4.0	4.0	4.0	mA
		LX25T	4.0	4.0	4.0	N/A	mA
		LX45	5.0	5.0	5.0	5.0	mA
		LX45T	5.0	5.0	5.0	N/A	mA
		LX75	7.0	7.0	7.0	7.0	mA
		LX75T	7.0	7.0	7.0	N/A	mA
		LX100	9.0	9.0	9.0	9.0	mA
		LX100T	9.0	9.0	9.0	N/A	mA
		LX150	12.0	12.0	12.0	12.0	mA
		LX150T	12.0	12.0	12.0	N/A	mA

Notes:

- Typical values are specified at nominal voltage, 25°C junction temperatures (T_j). Industrial (I) grade devices have the same typical values as commercial (C) grade devices at 25°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. Nominal V_{CCINT} is 1.20V; use the XPE tool to calculate 1.23V values for the nominal V_{CCINT} of the extended performance range.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- If differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 6: Power Supply Ramp Time

Symbol	Description	Speed Grade	Ramp Time	Units
V _{CCINTR}	Internal supply voltage ramp time	-3, -3N, -2	0.20 to 50.0	ms
		-1L	0.20 to 40.0	ms
V _{CCO2} ⁽¹⁾	Output drivers bank 2 supply voltage ramp time	All	0.20 to 50.0	ms
V _{CCAUXR}	Auxiliary supply voltage ramp time	All	0.20 to 50.0	ms

Notes:

- The minimum V_{CCO2} for power-on reset and configuration is 1.65V.
- Spartan-6 FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on ramp rate of the power supply. Use the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools to estimate current drain on these supplies. Spartan-6 devices do not have a required power-on sequence.

Table 10: Differential I/O Standard DC Input and Output Levels

I/O Standard	V _{ID}		V _{ICM}		V _{OD}		V _{OCM}		V _{OH}	V _{OL}
	mV, Min	mV, Max	V, Min	V, Max	mV, Min	mV, Max	V, Min	V, Max	V, Min	V, Max
LVDS_33 ⁽²⁾⁽³⁾	100	600	0.3	2.35	247	454	1.125	1.375	–	–
LVDS_25 ⁽²⁾⁽³⁾	100	600	0.3	2.35	247	454	1.125	1.375	–	–
BLVDS_25 ⁽²⁾⁽³⁾	100	–	0.3	2.35	240	460	Typical 50% V _{CCO}		–	–
MINI_LVDS_33	200	600	0.3	1.95	300	600	1.0	1.4	–	–
MINI_LVDS_25	200	600	0.3	1.95	300	600	1.0	1.4	–	–
LVPECL_33 ⁽²⁾⁽³⁾	100	1000	0.3	2.8 ⁽¹⁾	Inputs only					
LVPECL_25 ⁽²⁾⁽³⁾	100	1000	0.3	1.95	Inputs only					
RSDS_33 ⁽²⁾⁽³⁾	100	–	0.3	1.5	100	400	1.0	1.4	–	–
RSDS_25 ⁽²⁾⁽³⁾	100	–	0.3	1.5	100	400	1.0	1.4	–	–
TMDS_33	150	1200	2.7	3.23 ⁽¹⁾	400	800	V _{CCO} – 0.405	V _{CCO} – 0.190	–	–
PPDS_33 ⁽²⁾⁽³⁾	100	400	0.2	2.3	100	400	0.5	1.4	–	–
PPDS_25 ⁽²⁾⁽³⁾	100	400	0.2	2.3	100	400	0.5	1.4	–	–
DISPLAY_PORT	190	1260	0.3	2.35	–	–	Typical 50% V _{CCO}		–	–
DIFF_MOBILE_DDR	100	–	0.78	1.02	–	–	–	–	90% V _{CCO}	10% V _{CCO}
DIFF_HSTL_I	100	–	0.68	0.9	–	–	–	–	V _{CCO} – 0.4	0.4
DIFF_HSTL_II	100	–	0.68	0.9	–	–	–	–	V _{CCO} – 0.4	0.4
DIFF_HSTL_III	100	–	0.68	0.9	–	–	–	–	V _{CCO} – 0.4	0.4
DIFF_HSTL_I_18	100	–	0.8	1.1	–	–	–	–	V _{CCO} – 0.4	0.4
DIFF_HSTL_II_18	100	–	0.8	1.1	–	–	–	–	V _{CCO} – 0.4	0.4
DIFF_HSTL_III_18	100	–	0.8	1.1	–	–	–	–	V _{CCO} – 0.4	0.4
DIFF_SSTL3_I	100	–	1.0	1.9	–	–	–	–	V _{TT} + 0.6	V _{TT} – 0.6
DIFF_SSTL3_II	100	–	1.0	1.9	–	–	–	–	V _{TT} + 0.8	V _{TT} – 0.8
DIFF_SSTL2_I	100	–	1.0	1.5	–	–	–	–	V _{TT} + 0.61	V _{TT} – 0.61
DIFF_SSTL2_II	100	–	1.0	1.5	–	–	–	–	V _{TT} + 0.81	V _{TT} – 0.81
DIFF_SSTL18_I	100	–	0.7	1.1	–	–	–	–	V _{TT} + 0.47	V _{TT} – 0.47
DIFF_SSTL18_II	100	–	0.7	1.1	–	–	–	–	V _{TT} + 0.6	V _{TT} – 0.6
DIFF_SSTL15_II	100	–	0.55	0.95	–	–	–	–	V _{TT} + 0.4	V _{TT} – 0.4

Notes:

1. LVPECL_33 and TMDS_33 maximum V_{ICM} is the lower of V (maximum) or V_{CCAUX} – (V_{ID}/2)
2. When V_{CCAUX} = 3.3V, the DCD can be higher than 5% for V_{ICM} < 0.7V when using these I/O standards: LVDS_25, LVDS_33, BLVDS_25, LVPECL_25, LVPECL_33, RSDS_25, RSDS_33, PPDS_25, and PPDS_33.
3. The -1L devices require V_{CCAUX} = 2.5V when using the LVDS_25, LVDS_33, BLVDS_25, LVPECL_25, RSDS_25, RSDS_33, PPDS_25, and PPDS_33 I/O standards on inputs. LVPECL_33 is not supported in the -1L devices.

Table 17: GTP Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	200	800	2000	mV
R_{IN}	Differential input resistance	80	100	120	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTP Transceiver Switching Characteristics

Consult [UG386](#): *Spartan-6 FPGA GTP Transceivers User Guide* for further information.

Table 18: GTP Transceiver Performance

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
F_{GTPMAX}	Maximum GTP transceiver data rate	3.2	3.2	2.7	N/A	Gb/s
$F_{GTPRANGE1}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 1	1.88 to 3.2	1.88 to 3.2	1.88 to 2.7	N/A	Gb/s
$F_{GTPRANGE2}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 2	0.94 to 1.62	0.94 to 1.62	0.94 to 1.62	N/A	Gb/s
$F_{GTPRANGE3}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 4	0.6 to 0.81	0.6 to 0.81	0.6 to 0.81	N/A	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	1.62	1.62	1.62	N/A	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	0.94	0.94	0.94	N/A	GHz

Table 19: GTP Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
$F_{GTPDRCLK}$	GTP transceiver DCLK (DRP clock) maximum frequency	125	125	100	N/A	MHz

Table 20: GTP Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All LXT Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		60	–	160	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	1	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	200	μ s

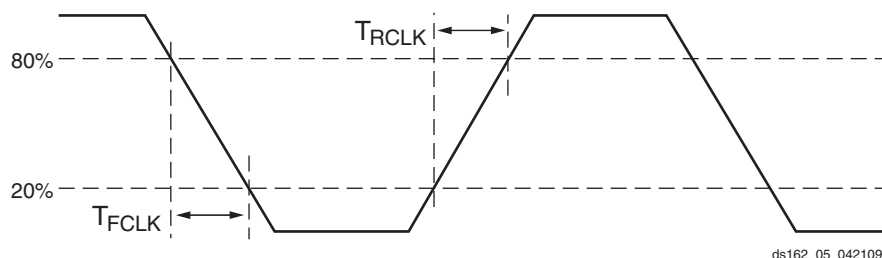


Figure 3: Reference Clock Timing Parameters

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases. [Table 27](#) lists the production released Spartan-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE® software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 27: Spartan-6 Device Production Software and Speed Specification Release⁽¹⁾

Device	Speed Grade Designations ⁽²⁾			
	-3 ⁽³⁾	-3N	-2 ⁽⁴⁾	-1L
XC6SLX4	ISE 12.4 v1.15	N/A	ISE 12.3 v1.12 ⁽⁵⁾	ISE 13.2 v1.07
XC6SLX9	ISE 12.4 v1.15	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.3 v1.12 ⁽⁵⁾	ISE 13.2 v1.07
XC6SLX16	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 11.5 v1.06	ISE 13.2 v1.07
XC6SLX25	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.2 v1.07
XC6SLX25T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX45	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 11.5 v1.07	ISE 13.1 v1.06
XC6SLX45T	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.1 v1.08	N/A
XC6SLX75	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.2 v1.07
XC6SLX75T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX100	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 v1.06
XC6SLX100T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX150	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 v1.06
XC6SLX150T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XA6SLX4	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX9	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX16	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX100	N/A	N/A	ISE 13.3 v1.20	N/A

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVDS_33	1.24	1.42	1.69	1.89	3000	3000	ns
LVDS_25	1.08	1.26	1.79	1.99	3000	3000	ns
BLVDS_25	1.09	1.27	1.86	2.06	1.86	2.06	ns
MINI_LVDS_33	1.25	1.43	1.71	1.91	3000	3000	ns
MINI_LVDS_25	1.08	1.26	1.79	1.99	3000	3000	ns
LVPECL_33	1.25	1.43	N/A	N/A	N/A	N/A	ns
LVPECL_25	1.09	1.27	N/A	N/A	N/A	N/A	ns
RSDS_33 (point to point)	1.24	1.42	1.71	1.91	3000	3000	ns
RSDS_25 (point to point)	1.08	1.26	1.79	1.99	3000	3000	ns
TMDS_33	1.29	1.47	1.68	1.88	3000	3000	ns
PPDS_33	1.25	1.43	1.71	1.91	3000	3000	ns
PPDS_25	1.08	1.26	1.82	2.02	3000	3000	ns
PCI33_3	1.14	1.32	3.81	4.01	3.81	4.01	ns
PCI66_3	1.14	1.32	3.81	4.01	3.81	4.01	ns
DISPLAY_PORT	1.09	1.27	3.29	3.49	3.29	3.49	ns
I2C	1.40	1.58	11.70	11.90	11.70	11.90	ns
SMBUS	1.40	1.58	11.70	11.90	11.70	11.90	ns
SDIO	1.43	1.61	2.78	2.98	2.78	2.98	ns
MOBILE_DDR	1.01	1.19	2.50	2.70	2.50	2.70	ns
HSTL_I	1.01	1.19	1.80	2.00	1.80	2.00	ns
HSTL_II	1.01	1.19	1.86	2.06	1.86	2.06	ns
HSTL_III	1.07	1.25	1.81	2.01	1.81	2.01	ns
HSTL_I_18	1.05	1.23	1.91	2.11	1.91	2.11	ns
HSTL_II_18	1.05	1.23	1.99	2.19	1.99	2.19	ns
HSTL_III_18	1.13	1.31	1.93	2.13	1.93	2.13	ns
SSTL3_I	1.65	1.83	1.97	2.17	1.97	2.17	ns
SSTL3_II	1.65	1.83	2.15	2.35	2.15	2.35	ns
SSTL2_I	1.37	1.55	1.91	2.11	1.91	2.11	ns
SSTL2_II	1.37	1.55	2.00	2.20	2.00	2.20	ns
SSTL18_I	0.99	1.17	1.77	1.97	1.77	1.97	ns
SSTL18_II	1.00	1.18	1.80	2.00	1.80	2.00	ns
SSTL15_II	1.00	1.18	1.81	2.01	1.81	2.01	ns
DIFF_HSTL_I	1.01	1.19	1.91	2.11	1.91	2.11	ns
DIFF_HSTL_II	1.00	1.18	1.86	2.06	1.86	2.06	ns
DIFF_HSTL_III	1.00	1.18	1.83	2.03	1.83	2.03	ns
DIFF_HSTL_I_18	1.04	1.22	1.93	2.13	1.93	2.13	ns
DIFF_HSTL_II_18	1.04	1.22	1.83	2.03	1.83	2.03	ns
DIFF_HSTL_III_18	1.04	1.22	1.83	2.03	1.83	2.03	ns

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVC MOS33, Slow, 6 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns
LVC MOS33, Slow, 8 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns
LVC MOS33, Slow, 12 mA	1.41	1.59	2.53	2.73	2.53	2.73	ns
LVC MOS33, Slow, 16 mA	1.41	1.59	2.45	2.65	2.45	2.65	ns
LVC MOS33, Slow, 24 mA	1.41	1.59	2.42	2.62	2.42	2.62	ns
LVC MOS33, Fast, 2 mA	1.41	1.59	4.05	4.25	4.05	4.25	ns
LVC MOS33, Fast, 4 mA	1.41	1.59	2.66	2.86	2.66	2.86	ns
LVC MOS33, Fast, 6 mA	1.41	1.59	2.46	2.66	2.46	2.66	ns
LVC MOS33, Fast, 8 mA	1.41	1.59	2.21	2.41	2.21	2.41	ns
LVC MOS33, Fast, 12 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns
LVC MOS33, Fast, 16 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns
LVC MOS33, Fast, 24 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns
LVC MOS25, QUIETIO, 2 mA	0.89	1.07	5.00	5.20	5.00	5.20	ns
LVC MOS25, QUIETIO, 4 mA	0.89	1.07	3.85	4.05	3.85	4.05	ns
LVC MOS25, QUIETIO, 6 mA	0.89	1.07	3.60	3.80	3.60	3.80	ns
LVC MOS25, QUIETIO, 8 mA	0.89	1.07	3.34	3.54	3.34	3.54	ns
LVC MOS25, QUIETIO, 12 mA	0.89	1.07	2.98	3.18	2.98	3.18	ns
LVC MOS25, QUIETIO, 16 mA	0.89	1.07	2.79	2.99	2.79	2.99	ns
LVC MOS25, QUIETIO, 24 mA	0.89	1.07	2.64	2.84	2.64	2.84	ns
LVC MOS25, Slow, 2 mA	0.89	1.07	3.96	4.16	3.96	4.16	ns
LVC MOS25, Slow, 4 mA	0.89	1.07	2.96	3.16	2.96	3.16	ns
LVC MOS25, Slow, 6 mA	0.89	1.07	2.88	3.08	2.88	3.08	ns
LVC MOS25, Slow, 8 mA	0.89	1.07	2.63	2.83	2.63	2.83	ns
LVC MOS25, Slow, 12 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns
LVC MOS25, Slow, 16 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns
LVC MOS25, Slow, 24 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns
LVC MOS25, Fast, 2 mA	0.89	1.07	3.52	3.72	3.52	3.72	ns
LVC MOS25, Fast, 4 mA	0.89	1.07	2.43	2.63	2.43	2.63	ns
LVC MOS25, Fast, 6 mA	0.89	1.07	2.23	2.43	2.23	2.43	ns
LVC MOS25, Fast, 8 mA	0.89	1.07	2.16	2.36	2.16	2.36	ns
LVC MOS25, Fast, 12 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns
LVC MOS25, Fast, 16 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns
LVC MOS25, Fast, 24 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns
LVC MOS18, QUIETIO, 2 mA	1.25	1.43	6.11	6.31	6.11	6.31	ns
LVC MOS18, QUIETIO, 4 mA	1.25	1.43	4.88	5.08	4.88	5.08	ns
LVC MOS18, QUIETIO, 6 mA	1.25	1.43	4.20	4.40	4.20	4.40	ns
LVC MOS18, QUIETIO, 8 mA	1.25	1.43	3.86	4.06	3.86	4.06	ns
LVC MOS18, QUIETIO, 12 mA	1.25	1.43	3.49	3.69	3.49	3.69	ns

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVC MOS12, QUIETIO, 6 mA	0.98	1.16	4.79	4.99	4.79	4.99	ns
LVC MOS12, QUIETIO, 8 mA	0.98	1.16	4.43	4.63	4.43	4.63	ns
LVC MOS12, QUIETIO, 12 mA	0.98	1.16	4.18	4.38	4.18	4.38	ns
LVC MOS12, Slow, 2 mA	0.98	1.16	5.12	5.32	5.12	5.32	ns
LVC MOS12, Slow, 4 mA	0.98	1.16	3.00	3.20	3.00	3.20	ns
LVC MOS12, Slow, 6 mA	0.98	1.16	2.91	3.11	2.91	3.11	ns
LVC MOS12, Slow, 8 mA	0.98	1.16	2.51	2.71	2.51	2.71	ns
LVC MOS12, Slow, 12 mA	0.98	1.16	2.25	2.45	2.25	2.45	ns
LVC MOS12, Fast, 2 mA	0.98	1.16	3.60	3.80	3.60	3.80	ns
LVC MOS12, Fast, 4 mA	0.98	1.16	2.49	2.69	2.49	2.69	ns
LVC MOS12, Fast, 6 mA	0.98	1.16	1.94	2.14	1.94	2.14	ns
LVC MOS12, Fast, 8 mA	0.98	1.16	1.82	2.02	1.82	2.02	ns
LVC MOS12, Fast, 12 mA	0.98	1.16	1.80	2.00	1.80	2.00	ns
LVC MOS12_JEDEC, QUIETIO, 2 mA	1.57	1.75	6.53	6.73	6.53	6.73	ns
LVC MOS12_JEDEC, QUIETIO, 4 mA	1.57	1.75	5.12	5.32	5.12	5.32	ns
LVC MOS12_JEDEC, QUIETIO, 6 mA	1.57	1.75	4.81	5.01	4.81	5.01	ns
LVC MOS12_JEDEC, QUIETIO, 8 mA	1.57	1.75	4.44	4.64	4.44	4.64	ns
LVC MOS12_JEDEC, QUIETIO, 12 mA	1.57	1.75	4.20	4.40	4.20	4.40	ns
LVC MOS12_JEDEC, Slow, 2 mA	1.57	1.75	5.14	5.34	5.14	5.34	ns
LVC MOS12_JEDEC, Slow, 4 mA	1.57	1.75	2.99	3.19	2.99	3.19	ns
LVC MOS12_JEDEC, Slow, 6 mA	1.57	1.75	2.90	3.10	2.90	3.10	ns
LVC MOS12_JEDEC, Slow, 8 mA	1.57	1.75	2.50	2.70	2.50	2.70	ns
LVC MOS12_JEDEC, Slow, 12 mA	1.57	1.75	2.26	2.46	2.26	2.46	ns
LVC MOS12_JEDEC, Fast, 2 mA	1.57	1.75	3.60	3.80	3.60	3.80	ns
LVC MOS12_JEDEC, Fast, 4 mA	1.57	1.75	2.49	2.69	2.49	2.69	ns
LVC MOS12_JEDEC, Fast, 6 mA	1.57	1.75	1.94	2.14	1.94	2.14	ns
LVC MOS12_JEDEC, Fast, 8 mA	1.57	1.75	1.83	2.03	1.83	2.03	ns
LVC MOS12_JEDEC, Fast, 12 mA	1.57	1.75	1.80	2.00	1.80	2.00	ns

Notes:

1. The Spartan-6Q FPGA -1L values are listed in Table 28.

Table 30 summarizes the value of T_{IOTPHZ}. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). These delays are measured using LVC MOS25, Fast, 12 mA.

Table 30: IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T _{IOTPHZ}	T input to Pad high-impedance	1.39	1.59	1.59	1.91	ns

Input Serializer/Deserializer Switching Characteristics

Table 37: ISERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold for Control Lines						
T _{ISCKC_BITSIP} / T _{ISCKC_BITSIP}	BITSIP pin Setup/Hold with respect to CLKDIV	0.16/ −0.09	0.20/ −0.09	0.31/ −0.09	0.34/ −0.14	ns
T _{ISCKC_CE} / T _{ISCKC_CE}	CE pin Setup/Hold with respect to CLK	0.71/ −0.47	0.71/ −0.42	0.97/ −0.42	1.39/ −0.71	ns
Setup/Hold for Data Lines						
T _{ISDCK_D} / T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.24/ −0.15	0.25/ −0.05	0.29/ −0.05	0.09/ −0.05	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	−0.25/ 0.30	−0.25/ 0.42	−0.25/ 0.56	−0.54/ 0.67	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	−0.03/ 0.04	−0.03/ 0.16	−0.03/ 0.18	−0.05/ 0.12	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY2)	−0.40/ 0.48	−0.40/ 0.53	−0.40/ 0.71	−0.71/ 0.86	ns
Sequential Delays						
T _{ISCKO_Q}	CLKDIV to out at Q pin	1.30	1.44	2.02	2.22	ns
F _{CLKDIV}	CLKDIV maximum frequency	270	262.5	250	125	MHz

Output Serializer/Deserializer Switching Characteristics

Table 38: OSERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	−0.03/ 1.02	−0.03/ 1.17	−0.03/ 1.27	−0.02/ 0.23	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	−0.05/ 1.03	−0.05/ 1.13	−0.05/ 1.23	−0.05/ 0.24	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.12/ −0.03	0.15/ −0.03	0.24/ −0.03	0.28/ −0.17	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.14/ −0.08	0.17/ −0.08	0.27/ −0.08	0.31/ −0.16	ns
Sequential Delays						
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.94	1.11	1.51	1.89	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.94	1.11	1.51	1.91	ns
F _{CLKDIV}	CLKDIV maximum frequency	270	262.5	250	125	MHz

Notes:

- $T_{OSDCK_T2} / T_{OSCKD_T2}$ (T input setup/hold with respect to CLKDIV) are reported as $T_{OSDCK_T} / T_{OSCKD_T}$ in TRACE report.

CLB Switching Characteristics (SLICEM Only)

Table 40: CLB Switching Characteristics (SLICEM Only)

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT inputs to A to D outputs	0.21	0.26	0.26	0.46	ns, Max
	An – Dn LUT inputs through F7AMUX/F7BMUX to AMUX/CMUX output	0.37	0.43	0.43	0.77	ns, Max
T _{OPAB}	An – Dn LUT inputs through F7AMUX or F7BMUX and F8MUX to BMUX output	0.37	0.46	0.46	0.84	ns, Max
T _{ITO}	An – Dn LUT inputs through latch to AQ – DQ outputs	0.82	0.95	0.95	1.64	ns, Max
T _{TITO_LOGIC}	An – Dn LUT inputs to AQ – DQ outputs (latch as logic)	0.82	0.95	0.95	1.64	ns, Max
T _{OPCYA}	An LUT inputs to COUT output	0.38	0.48	0.48	0.69	ns, Max
T _{OPCYB}	Bn LUT inputs to COUT output	0.38	0.49	0.49	0.71	ns, Max
T _{OPCYC}	Cn LUT inputs to COUT output	0.28	0.33	0.33	0.55	ns, Max
T _{OPCYD}	Dn LUT inputs to COUT output	0.28	0.35	0.35	0.52	ns, Max
T _{AXCY}	AX input to COUT output	0.21	0.26	0.26	0.36	ns, Max
T _{BXCy}	BX input to COUT output	0.13	0.16	0.16	0.18	ns, Max
T _{CXCy}	CX input to COUT output	0.10	0.12	0.12	0.09	ns, Max
T _{DXCy}	DX input to COUT output	0.09	0.11	0.11	0.09	ns, Max
T _{BYP}	CIN input to COUT output	0.08	0.10	0.10	0.06	ns, Max
T _{CINA}	CIN input to AMUX output	0.21	0.22	0.22	0.47	ns, Max
T _{CINB}	CIN input to BMUX output	0.30	0.31	0.31	0.57	ns, Max
T _{CINC}	CIN input to CMUX output	0.29	0.31	0.31	0.58	ns, Max
T _{CIND}	CIN input to DMUX output	0.31	0.32	0.32	0.68	ns, Max
Sequential Delays						
T _{CKO}	Clock to AQ – DQ outputs	0.45	0.53	0.53	0.74	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T _{DICK} /T _{CKDI}	AX – DX input to CLK on A – D flip-flops	0.42/ 0.28	0.47/ 0.39	0.47/ 0.39	0.90/ 0.56	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK on A – D flip-flops	0.31/ –0.07	0.37/ –0.07	0.37/ –0.07	0.59/ –0.27	ns, Min
T _{SRCK} /T _{CKSR}	SR input to CLK on A – D flip-flops for XC devices	0.41/ 0.02	0.42/ 0.02	0.42/ 0.02	0.68/ –0.29	ns, Min
	SR input to CLK on A – D flip-flops for XA and XQ devices	0.41/ 0.02	N/A	0.44/ 0.02	0.68/ –0.29	ns, Min
T _{CINCK} /T _{CKCIN}	CIN input to CLK on A – D flip-flops	0.31/ –0.17	0.31/ –0.13	0.31/ –0.13	0.81/ –0.42	ns, Min
Set/Reset						
T _{RPW}	SR input minimum pulse width	0.41	0.48	0.48	1.37	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.60	0.70	0.70	0.88	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.60	0.65	0.65	0.90	ns, Max
F _{TOG}	Toggle frequency (for export control)	862	806	667	500	MHz

Table 45: Device DNA Interface Port Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T _{DNASSU}	Setup time on SHIFT before the rising edge of CLK	7				ns, Min
T _{DNASH}	Hold time on SHIFT after the rising edge of CLK	1				ns, Min
T _{DNADSU}	Setup time on DIN before the rising edge of CLK	7				ns, Min
T _{DNADH}	Hold time on DIN after the rising edge of CLK	1				ns, Min
T _{DNARSU}	Setup time on READ before the rising edge of CLK	7				ns, Min
		1,000				ns, Max
T _{DNARH}	Hold time on READ after the rising edge of CLK	1				ns, Min
T _{DNADCKO}	Clock-to-output delay on DOUT after rising edge of CLK	0.5				ns, Min
		6				ns, Max
T _{DNACKF} ⁽²⁾	CLK frequency	2				MHz, Max
T _{DNACKL}	CLK Low time	50				ns, Min
T _{DNACKH}	CLK High time	50				ns, Min

Notes:

1. The minimum READ pulse width is 8 ns, the maximum READ pulse width is 1 μ s.
2. Also applies to TCK when reading DNA through the boundary-scan port.

Table 46: Suspend Mode Switching Characteristics

Symbol	Description	Min	Max	Units
Entering Suspend Mode				
T _{SUSPENDHIGH_AWAKE}	Rising edge of SUSPEND pin to falling edge of AWAKE pin without glitch filter	2.5	14	ns
T _{SUSPENDFILTER}	Adjustment to SUSPEND pin rising edge parameters when glitch filter enabled	31	430	ns
T _{SUSPEND_GWE}	Rising edge of SUSPEND pin until FPGA output pins drive their defined SUSPEND constraint behavior (without glitch filter)	–	15	ns
T _{SUSPEND_GTS}	Rising edge of SUSPEND pin to write-protect lock on all writable clocked elements (without glitch filter)	–	15	ns
T _{SUSPEND_DISABLE}	Rising edge of the SUSPEND pin to FPGA input pins and interconnect disabled (without glitch filter)	–	1500	ns
Exiting Suspend Mode				
T _{SUSPENDLOW_AWAKE}	Falling edge of the SUSPEND pin to rising edge of the AWAKE pin. Does not include DCM or PLL lock time.	7	75	μ s
T _{SUSPEND_ENABLE}	Falling edge of the SUSPEND pin to FPGA input pins and interconnect re-enabled	7	41	μ s
T _{AWAKE_GWE1}	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using sw_clk:InternalClock and sw_gwe_cycle:1 .	–	80	ns
T _{AWAKE_GWE512}	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using sw_clk:InternalClock and sw_gwe_cycle:512 .	–	20.5	μ s
T _{AWAKE_GTS1}	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using sw_clk:InternalClock and sw_gts_cycle:1 .	–	80	ns
T _{AWAKE_GTS512}	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using sw_clk:InternalClock and sw_gts_cycle:512 .	–	20.5	μ s
T _{SCP_AWAKE}	Rising edge of SCP pins to rising edge of AWAKE pin	7	75	μ s

Spartan-6 Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 63 through Table 69. Values are expressed in nanoseconds unless otherwise noted.

Table 63: Global Clock Input to Output Delay Without DCM or PLL

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> DCM or PLL							
T _{ICKOF}	Global Clock and OUTFF <i>without</i> DCM or PLL	XC6SLX4	6.12	N/A	7.68	9.41	ns
		XC6SLX9	6.12	6.51	7.68	9.41	ns
		XC6SLX16	5.98	6.42	7.48	9.10	ns
		XC6SLX25	6.20	6.69	7.84	9.44	ns
		XC6SLX25T	6.20	6.69	7.84	N/A	ns
		XC6SLX45	6.37	6.88	8.10	9.61	ns
		XC6SLX45T	6.37	6.88	8.10	N/A	ns
		XC6SLX75	6.39	6.99	8.16	10.18	ns
		XC6SLX75T	6.39	6.99	8.16	N/A	ns
		XC6SLX100	6.59	7.18	8.41	10.31	ns
		XC6SLX100T	6.59	7.18	8.41	N/A	ns
		XC6SLX150	6.98	7.68	8.80	10.62	ns
		XC6SLX150T	6.98	7.68	8.80	N/A	ns
		XA6SLX4	6.44	N/A	7.68	N/A	ns
		XA6SLX9	6.44	N/A	7.68	N/A	ns
		XA6SLX16	6.30	N/A	7.48	N/A	ns
		XA6SLX25	6.52	N/A	7.84	N/A	ns
		XA6SLX25T	6.52	N/A	7.84	N/A	ns
		XA6SLX45	6.69	N/A	8.12	N/A	ns
		XA6SLX45T	6.69	N/A	8.12	N/A	ns
		XA6SLX75	6.89	N/A	8.16	N/A	ns
		XA6SLX75T	6.89	N/A	8.16	N/A	ns
		XA6SLX100	N/A	N/A	8.36	N/A	ns
		XQ6SLX75	N/A	N/A	8.16	10.18	ns
		XQ6SLX75T	6.89	N/A	8.16	N/A	ns
		XQ6SLX150	N/A	N/A	8.80	10.62	ns
		XQ6SLX150T	7.61	N/A	8.80	N/A	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 65: Global Clock Input to Output Delay With DCM in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in Source-Synchronous Mode.							
T _{ICKOFDCM_0}	Global Clock and OUTFF <i>with</i> DCM	XC6SLX4	5.03	N/A	7.21	8.05	ns
		XC6SLX9	5.03	6.13	7.21	8.05	ns
		XC6SLX16	5.08	5.51	6.44	7.96	ns
		XC6SLX25	4.81	5.13	5.69	7.94	ns
		XC6SLX25T	4.81	5.13	5.69	N/A	ns
		XC6SLX45	5.26	5.69	6.63	7.92	ns
		XC6SLX45T	5.26	5.69	6.63	N/A	ns
		XC6SLX75	4.77	5.18	5.88	7.95	ns
		XC6SLX75T	4.77	5.18	5.88	N/A	ns
		XC6SLX100	4.72	5.11	5.76	8.59	ns
		XC6SLX100T	4.76	5.11	5.76	N/A	ns
		XC6SLX150	4.90	5.30	5.93	7.93	ns
		XC6SLX150T	4.90	5.30	5.93	N/A	ns
		XA6SLX4	5.35	N/A	7.21	N/A	ns
		XA6SLX9	5.35	N/A	7.21	N/A	ns
		XA6SLX16	5.42	N/A	6.44	N/A	ns
		XA6SLX25	5.13	N/A	5.69	N/A	ns
		XA6SLX25T	5.13	N/A	5.79	N/A	ns
		XA6SLX45	5.58	N/A	6.63	N/A	ns
		XA6SLX45T	5.58	N/A	6.63	N/A	ns
		XA6SLX75	5.09	N/A	5.87	N/A	ns
		XA6SLX75T	5.09	N/A	5.87	N/A	ns
		XA6SLX100	N/A	N/A	6.44	N/A	ns
		XQ6SLX75	N/A	N/A	5.87	7.95	ns
		XQ6SLX75T	5.09	N/A	5.87	N/A	ns
		XQ6SLX150	N/A	N/A	6.06	7.93	ns
		XQ6SLX150T	5.50	N/A	6.06	N/A	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
- DCM output jitter is already included in the timing calculation.

Table 69: Global Clock Input to Output Delay With DCM and PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in Source-Synchronous Mode and PLL in DCM2PLL Mode.							
T _{ICKOFDCM0_PLL}	Global Clock and OUTFF with DCM and PLL	XC6SLX4	5.58	N/A	7.42	8.54	ns
		XC6SLX9	5.58	6.19	7.42	8.54	ns
		XC6SLX16	5.50	6.06	7.05	8.24	ns
		XC6SLX25	5.57	6.04	7.02	8.33	ns
		XC6SLX25T	5.57	6.04	7.02	N/A	ns
		XC6SLX45	5.53	5.97	6.96	8.32	ns
		XC6SLX45T	5.53	5.97	6.96	N/A	ns
		XC6SLX75	5.55	6.00	6.99	8.54	ns
		XC6SLX75T	5.55	6.00	6.99	N/A	ns
		XC6SLX100	5.58	6.03	7.02	9.11	ns
		XC6SLX100T	5.62	6.03	7.02	N/A	ns
		XC6SLX150	5.32	5.70	6.41	8.26	ns
		XC6SLX150T	5.32	5.70	6.41	N/A	ns
		XA6SLX4	5.87	N/A	7.28	N/A	ns
		XA6SLX9	5.87	N/A	7.28	N/A	ns
		XA6SLX16	6.02	N/A	6.87	N/A	ns
		XA6SLX25	5.88	N/A	6.90	N/A	ns
		XA6SLX25T	5.88	N/A	7.00	N/A	ns
		XA6SLX45	5.82	N/A	6.81	N/A	ns
		XA6SLX45T	5.82	N/A	6.81	N/A	ns
		XA6SLX75	5.81	N/A	6.80	N/A	ns
		XA6SLX75T	5.81	N/A	6.80	N/A	ns
		XA6SLX100	N/A	N/A	6.88	N/A	ns
		XQ6SLX75	N/A	N/A	6.80	8.54	ns
		XQ6SLX75T	5.81	N/A	6.80	N/A	ns
		XQ6SLX150	N/A	N/A	6.41	8.26	ns
		XQ6SLX150T	5.90	N/A	6.41	N/A	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM and PLL output jitter are already included in the timing calculation.

Spartan-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 70 through Table 77. Values are expressed in nanoseconds unless otherwise noted.

Table 70: Global Clock Setup and Hold Without DCM or PLL (No Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.(1)							
T _{PSND} / T _{PHND}	No Delay Global Clock and IFF(3) without DCM or PLL	XC6SLX4	0.10/1.56	N/A	0.10/1.83	0.07/2.54	ns
		XC6SLX9	0.10/1.56	0.10/1.57	0.10/1.84	0.07/2.54	ns
		XC6SLX16	0.12/1.42	0.12/1.48	0.12/1.64	0.13/2.19	ns
		XC6SLX25	0.18/1.64	0.18/1.75	0.18/1.99	0.11/2.57	ns
		XC6SLX25T	0.18/1.64	0.18/1.75	0.18/1.99	N/A	ns
		XC6SLX45	−0.08/1.80	−0.08/1.95	−0.08/2.27	−0.17/2.74	ns
		XC6SLX45T	−0.08/1.80	−0.08/1.95	−0.08/2.27	N/A	ns
		XC6SLX75	0.13/1.81	0.13/2.06	0.13/2.27	−0.12/3.30	ns
		XC6SLX75T	0.13/1.81	0.13/2.06	0.13/2.27	N/A	ns
		XC6SLX100	−0.14/2.03	−0.14/2.24	−0.14/2.56	−0.17/3.44	ns
		XC6SLX100T	−0.14/2.03	−0.14/2.24	−0.14/2.56	N/A	ns
		XC6SLX150	−0.24/2.42	−0.24/2.74	−0.24/2.95	−0.60/3.75	ns
		XC6SLX150T	−0.24/2.42	−0.24/2.74	−0.24/2.95	N/A	ns
		XA6SLX4	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX9	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX16	0.12/1.43	N/A	0.12/1.64	N/A	ns
		XA6SLX25	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX25T	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX45	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX45T	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX75	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX100	N/A	N/A	0.10/2.51	N/A	ns
		XQ6SLX75	N/A	N/A	0.13/2.32	−0.12/3.30	ns
		XQ6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XQ6SLX150	N/A	N/A	−0.24/2.95	−0.60/3.75	ns
		XQ6SLX150T	−0.24/2.74	N/A	−0.24/2.95	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch.

Table 72: Global Clock Setup and Hold With DCM in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard. ⁽¹⁾							
T _{PSDCM} / T _{PHDCM}	No Delay Global Clock and IFF ⁽²⁾ with DCM in System-Synchronous Mode	XC6SLX4	1.54/0.06	N/A	1.75/0.12	2.84/0.27	ns
		XC6SLX9	1.54/0.06	1.63/0.12	1.75/0.12	2.84/0.27	ns
		XC6SLX16	1.72/−0.18	1.87/−0.17	2.13/−0.17	2.31/0.26	ns
		XC6SLX25	1.70/−0.03	1.78/−0.02	2.00/−0.02	2.88/0.20	ns
		XC6SLX25T	1.70/0.07	1.78/0.08	2.00/0.08	N/A	ns
		XC6SLX45	1.74/−0.03	1.84/−0.02	2.02/−0.02	2.64/0.52	ns
		XC6SLX45T	1.74/−0.01	1.84/0.00	2.02/0.00	N/A	ns
		XC6SLX75	1.86/0.11	1.98/0.12	2.20/0.12	2.96/0.58	ns
		XC6SLX75T	1.86/0.11	1.98/0.12	2.20/0.12	N/A	ns
		XC6SLX100	1.64/0.07	1.72/0.08	1.97/0.08	2.70/0.99	ns
		XC6SLX100T	1.64/0.09	1.72/0.10	1.97/0.10	N/A	ns
		XC6SLX150	1.53/0.39	1.62/0.40	1.82/0.40	2.75/1.00	ns
		XC6SLX150T	1.53/0.39	1.62/0.40	1.82/0.40	N/A	ns
		XA6SLX4	1.65/0.16	N/A	1.75/0.26	N/A	ns
		XA6SLX9	1.65/0.16	N/A	1.75/0.26	N/A	ns
		XA6SLX16	1.88/0.02	N/A	2.13/0.03	N/A	ns
		XA6SLX25	1.80/0.16	N/A	2.05/0.17	N/A	ns
		XA6SLX25T	1.80/0.16	N/A	2.13/0.17	N/A	ns
		XA6SLX45	1.75/0.12	N/A	2.02/0.13	N/A	ns
		XA6SLX45T	1.75/0.12	N/A	2.02/0.13	N/A	ns
		XA6SLX75	1.87/0.11	N/A	2.20/0.12	N/A	ns
		XA6SLX75T	1.87/0.11	N/A	2.20/0.12	N/A	ns
		XA6SLX100	N/A	N/A	2.46/0.24	N/A	ns
		XQ6SLX75	N/A	N/A	2.20/0.12	2.96/0.58	ns
		XQ6SLX75T	1.87/0.11	N/A	2.20/0.12	N/A	ns
		XQ6SLX150	N/A	N/A	1.82/0.56	2.75/1.00	ns
		XQ6SLX150T	1.65/0.55	N/A	1.82/0.56	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 73: Global Clock Setup and Hold With DCM in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSDCM0} / T _{PHDCM0}	No Delay Global Clock and IFF ⁽²⁾ with DCM in Source-Synchronous Mode	XC6SLX4	0.71/0.65	N/A	0.72/1.22	1.58/1.18	ns
		XC6SLX9	0.71/0.69	0.71/1.19	0.72/1.36	1.58/1.18	ns
		XC6SLX16	0.86/0.52	0.92/0.57	1.04/0.60	1.02/1.06	ns
		XC6SLX25	0.84/0.58	0.90/0.59	1.01/0.59	1.58/1.07	ns
		XC6SLX25T	0.84/0.58	0.90/0.59	1.01/0.59	N/A	ns
		XC6SLX45	0.85/0.70	0.90/0.76	0.98/0.79	1.34/1.34	ns
		XC6SLX45T	0.85/0.70	0.90/0.76	0.98/0.79	N/A	ns
		XC6SLX75	1.00/0.62	1.06/0.63	1.15/0.63	1.65/1.46	ns
		XC6SLX75T	1.00/0.71	1.06/0.72	1.15/0.72	N/A	ns
		XC6SLX100	0.81/0.68	0.81/0.69	0.94/0.69	1.42/2.07	ns
		XC6SLX100T	0.81/0.68	0.81/0.69	0.94/0.69	N/A	ns
		XC6SLX150	0.68/0.98	0.69/0.99	0.79/0.99	1.45/1.60	ns
		XC6SLX150T	0.68/0.98	0.69/0.99	0.79/0.99	N/A	ns
		XA6SLX4	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX9	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX16	1.01/0.56	N/A	1.04/0.60	N/A	ns
		XA6SLX25	0.94/0.76	N/A	1.06/0.77	N/A	ns
		XA6SLX25T	0.94/0.76	N/A	1.14/0.77	N/A	ns
		XA6SLX45	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX45T	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX75	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX100	N/A	N/A	1.37/0.75	N/A	ns
		XQ6SLX75	N/A	N/A	1.15/0.72	1.65/1.46	ns
		XQ6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XQ6SLX150	N/A	N/A	0.79/1.15	1.45/1.60	ns
		XQ6SLX150T	0.73/1.15	N/A	0.79/1.15	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 77: Global Clock Setup and Hold With DCM and PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Example Data Input Set-Up and Hold Times Relative to a Forwarded Clock Input Pin, ⁽¹⁾ Using DCM, PLL, and Global Clock Buffer for the LVCMOS25 standard.							
T _{PSDCMPLL_0} / T _{PHDCMPLL_0}	No Delay Global Clock and IFF ⁽²⁾ with DCM in Source-Synchronous Mode and PLL in DCM2PLL Mode.	XC6SLX4	0.43/1.07	N/A	0.43/1.43	1.10/1.67	ns
		XC6SLX9	0.43/1.03	0.45/1.14	0.45/1.43	1.10/1.67	ns
		XC6SLX16	0.74/0.93	0.74/1.12	0.74/1.21	0.77/1.35	ns
		XC6SLX25	0.67/1.02	0.76/1.11	0.84/1.18	1.23/1.46	ns
		XC6SLX25T	0.67/1.02	0.76/1.11	0.84/1.18	N/A	ns
		XC6SLX45	0.65/0.99	0.65/1.04	0.71/1.12	1.18/1.58	ns
		XC6SLX45T	0.65/1.00	0.65/1.04	0.71/1.12	N/A	ns
		XC6SLX75	0.86/1.01	0.88/1.06	0.94/1.14	1.29/1.67	ns
		XC6SLX75T	0.86/1.01	0.88/1.06	0.94/1.14	N/A	ns
		XC6SLX100	0.50/1.10	0.56/1.10	0.61/1.17	0.84/2.24	ns
		XC6SLX100T	0.50/1.10	0.56/1.10	0.61/1.17	N/A	ns
		XC6SLX150	0.45/1.28	0.47/1.28	0.52/1.28	1.27/1.56	ns
		XC6SLX150T	0.45/1.28	0.47/1.28	0.52/1.28	N/A	ns
		XA6SLX4	0.74/1.00	N/A	0.74/1.43	N/A	ns
		XA6SLX9	0.74/1.00	N/A	0.74/1.43	N/A	ns
		XA6SLX16	1.81/1.15	N/A	1.81/1.03	N/A	ns
		XA6SLX25	0.89/1.01	N/A	0.96/1.05	N/A	ns
		XA6SLX25T	0.89/1.01	N/A	1.04/1.15	N/A	ns
		XA6SLX45	0.69/0.95	N/A	0.83/0.96	N/A	ns
		XA6SLX45T	0.69/0.95	N/A	0.83/0.96	N/A	ns
		XA6SLX75	0.88/0.94	N/A	1.06/0.96	N/A	ns
		XA6SLX75T	0.88/0.94	N/A	1.06/0.96	N/A	ns
		XA6SLX100	N/A	N/A	1.55/1.33	N/A	ns
		XQ6SLX75	N/A	N/A	1.06/0.96	1.29/1.67	ns
		XQ6SLX75T	0.88/0.94	N/A	1.06/0.96	N/A	ns
		XQ6SLX150	N/A	N/A	0.64/1.30	1.27/1.56	ns
		XQ6SLX150T	0.58/1.30	N/A	0.64/1.30	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. The timing values were measured using the fine-phase adjustment feature of the DCM. These measurements include CMT jitter; DCM CLK0 driving PLL, PLL CLKOUT0 driving BUFG. Package skew is not included in these measurements.
- IFF = Input Flip-Flop

Table 79: Package Skew (Cont'd)

Symbol	Description	Device	Package ⁽²⁾	Value	Units
T _{PKGSKEW}	Package Skew ⁽¹⁾	LX45	CSG324	70	ps
			CS(G)484	99	ps
			FG(G)484	109	ps
			FG(G)676	138	ps
		LX45T	CSG324	75	ps
			CS(G)484	100	ps
			FG(G)484	95	ps
		LX75	CS(G)484	101	ps
			FG(G)484	107	ps
			FG(G)676	161	ps
		LX75T	CS(G)484	107	ps
			FG(G)484	110	ps
			FG(G)676	134	ps
		LX100	CS(G)484	95	ps
			FG(G)484	155	ps
			FG(G)676	144	ps
		LX100T	CS(G)484	88	ps
			FG(G)484	111	ps
			FG(G)676	147	ps
			FG(G)900	134	ps
		LX150	CS(G)484	84	ps
			FG(G)484	103	ps
			FG(G)676	115	ps
			FG(G)900	121	ps
		LX150T	CS(G)484	83	ps
			FG(G)484	88	ps
			FG(G)676	141	ps
			FG(G)900	120	ps

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from Pad to Ball.
- Some of the devices are available in both Pb and Pb-free (additional G) packages as standard ordering options. See [DS160: Spartan-6 Family Overview](#) for more information.

Table 80: Sample Window

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽²⁾	All	510	510	530	740	ps
T _{SAMP_BUFIO2}	Sampling Error at Receiver Pins using BUFIO2 ⁽³⁾	All	430	430	450	590	ps

Notes:

- LXT devices are not available with a -1L speed grade.
- This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the DCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 DCM jitter
 - DCM accuracy (phase offset)
 - DCM phase shift resolution
These measurements do not include package or clock tree skew.
- This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO2 clock network and IODELAY2 to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Date	Version	Description of Revisions
06/14/10	1.5	In Table 2, added note 5 and added temperature range to V_{FS} and R_{FUSE}. Removed speed grade delineation, revised I_{RPD} description, and updated note 2 in Table 4. Added note 2 to Table 7. Added $DIFF_MOBILE_DDR$ to Table 8 and Table 10. Added note 4 to Table 15. Changed minimum DV_{PPIN} in Table 16. Updated $F_{GTPDRCLK}$ in Table 19. Increased maximum T_{LLSKEW} in Table 22. Updated descriptions and added data to Table 23. Removed note 1 and added new data to the Networking Applications section in Table 25. Updated Table 26 and Table 27 to the data in ISE v12.1 software with speed specification v1.08. In Table 28, added $DIFF_MOBILE_DDR$ and updated -4 speed grade data. Updated the maximum I/O pairs per bank in Table 33. Updated note 2 on Table 39. Revised the F_{MAX} in Table 44. In Table 47, updated description for $T_{SMCKCSO}$, revised values for T_{POR} and added Min value, added $T_{BPIICCK}$ and $T_{SPIICCK}$. Also in Table 47, added device dependencies to F_{SMCKCK} and F_{RBCKCK}. Updated and added data to Table 63 through Table 78, and Table 81. In Table 79, added data on the XC6SLX45-FG(G)676 and revised the XC6SLX45T and XC6SLX150T values. The following changes to this specification are addressed in the product change notice XC6SLX45-FG(G)676, <i>MCB Performance and JTAG Revision Code for Spartan-6 LX16 and LX45 FPGAs</i>. In Table 2, revised the V_{CCINT} to add the memory controller block extended performance specifications. In Table 25, changed the standard specifications and added extended performance specifications for the memory controller block and note 2. Added note 4 and updated values in Table 34.
06/24/10	1.6	Production release of XC6SLX45T (-2 and -3 speed grades), XC6SLX16 and XC6SLX45 (-3 speed grade) devices which includes changes to Table 26 and Table 27 (ISE v12.1 software with speed specification v1.08). Added the -3N speed grade, which designates Spartan-6 devices that do not support MCB functionality. This includes changes to Table 2 (note 2), Table 25 (note 4), and Switching Characteristics (Table 26). Updated Simultaneously Switching Outputs discussion. Added -3 speed grade values for T_{TAP} and F_{MINCAL} values in Table 39. In Table 40, updated T_{RPW} (-2 and -3 speed grade) values and F_{TOG} (-3 speed grade) values. In Table 48, updated T_{GIO} (-2 and -3 speed grade) values. Updated -3 values in spread spectrum section of Table 57.
07/16/10	1.7	Production release of specific devices listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 4 advising designers of the patch which contains v1.11. Also updated the -1L speed specification to v1.04. Updated numerous -4 and -1L values. Added -4 T_{TAP} values and F_{MINCAL} to Table 39. Revised T_{CINCK}/T_{CKCIN} in Table 40. In Table 41, revised T_{SHCKO}. In Table 42, revised T_{REQ}. Added new -1L values to Table 47. Added and updated values in Table 79.
07/26/10	1.8	Production release of XC6SLX25, XC6SLX25T, XC6SLX100 and XC6SLX100T in the specific speed grades listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 7 to Table 2 and moved V_{FS} and R_{FUSE} to a new Table 3. Added I_{HS} and note 4 to Table 4. Added note 1 to Table 28. Added and updated SSO limits per V_{CCO}/GND pairs in Table 34. Added note 3 to Table 47. In Table 54, removed -1L specifications for $CLKOUT_PER_JITT_DV1/2$ and revised $CLKIN_CLKFB_PHASE$ and $CLKOUT_PHASE_DLL$ values. Updated note 3 in both Table 56 and Table 57.
08/23/10	1.9	Updated values for $F_{GTPRANGE1}$, $F_{GTPRANGE2}$, and $F_{GPLLMIN}$ in Table 18. Revised -3 and -4 values in Table 21. Removed the -1L speed grade readback support restriction and note 3 in Table 47.
11/05/10	1.10	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.3 software with speed specification v1.12 for the -2 speed grade available in the 12.3 <i>Speed Files Patch</i>. Added note 3 advising designers of the patch which contains v1.12. In Table 2, added note 4. In Table 4, added note 2. In Table 10, added notes 2 and 3. In Table 44, added note 2. In Table 47, updated symbol for $T_{SMWCKCK}/T_{SMCKCKW}$, changed -1L values for $T_{USERCCLKH}$ and $T_{USERCCLKL}$, and added and revised the modes for F_{MCKCK} and F_{SMCKCK}. In Table 53, redefined and expanded description for $CLKIN_FREQ_DLL$ and rewrote note 3. Updated title of Table 58. Also in Table 78, revised T_{DCD_CLK} for XC6SLX150 and XC6SLX150T. Changed description of T_{PSFD}/T_{PHFD} in Table 71. For the -1L speed grade, updated data sheet to ISE 12.3 software with speed specification v1.05 which revised the values in the following tables: Table 25, Table 28, Table 35, Table 36, Table 37, Table 40 through Table 43, Table 48 through Table 56, Table 62 through Table 78, Table 80, and Table 81. Updated Notice of Disclaimer.